# E·XFL

## Intel - EPM7128AELC84-7 Datasheet



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#### Understanding <u>Embedded - CPLDs (Complex</u> <u>Programmable Logic Devices)</u>

Embedded - CPLDs, or Complex Programmable Logic Devices, are highly versatile digital logic devices used in electronic systems. These programmable components are designed to perform complex logical operations and can be customized for specific applications. Unlike fixedfunction ICs, CPLDs offer the flexibility to reprogram their configuration, making them an ideal choice for various embedded systems. They consist of a set of logic gates and programmable interconnects, allowing designers to implement complex logic circuits without needing custom hardware.

#### **Applications of Embedded - CPLDs**

#### Details

Product Status	Obsolete
Programmable Type	In System Programmable
Delay Time tpd(1) Max	7.5 ns
Voltage Supply - Internal	3V ~ 3.6V
Number of Logic Elements/Blocks	8
Number of Macrocells	128
Number of Gates	2500
Number of I/O	68
Operating Temperature	0°C ~ 70°C (TA)
Mounting Type	Surface Mount
Package / Case	84-LCC (J-Lead)
Supplier Device Package	84-PLCC (29.31x29.31)
Purchase URL	https://www.e-xfl.com/product-detail/intel/epm7128aelc84-7

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Table 1. MAX 7000A Device Features								
Feature	EPM7032AE	EPM7064AE	EPM7128AE	EPM7256AE	EPM7512AE			
Usable gates	600	1,250	2,500	5,000	10,000			
Macrocells	32	64	128	256	512			
Logic array blocks	2	4	8	16	32			
Maximum user I/O pins	36	68	100	164	212			
t <sub>PD</sub> (ns)	4.5	4.5	5.0	5.5	7.5			
t <sub>SU</sub> (ns)	2.9	2.8	3.3	3.9	5.6			
t <sub>FSU</sub> (ns)	2.5	2.5	2.5	2.5	3.0			
t <sub>CO1</sub> (ns)	3.0	3.1	3.4	3.5	4.7			
f <sub>CNT</sub> (MHz)	227.3	222.2	192.3	172.4	116.3			

# ...and More Features

- 4.5-ns pin-to-pin logic delays with counter frequencies of up to 227.3 MHz
- MultiVolt<sup>™</sup> I/O interface enables device core to run at 3.3 V, while I/O pins are compatible with 5.0-V, 3.3-V, and 2.5-V logic levels
- Pin counts ranging from 44 to 256 in a variety of thin quad flat pack (TQFP), plastic quad flat pack (PQFP), ball-grid array (BGA), spacesaving FineLine BGA<sup>™</sup>, and plastic J-lead chip carrier (PLCC) packages
- Supports hot-socketing in MAX 7000AE devices
- Programmable interconnect array (PIA) continuous routing structure for fast, predictable performance
- PCI-compatible
- Bus-friendly architecture, including programmable slew-rate control
- Open-drain output option
- Programmable macrocell registers with individual clear, preset, clock, and clock enable controls
- Programmable power-up states for macrocell registers in MAX 7000AE devices
- Programmable power-saving mode for 50% or greater power reduction in each macrocell
- Configurable expander product-term distribution, allowing up to 32 product terms per macrocell
- Programmable security bit for protection of proprietary designs
- 6 to 10 pin- or logic-driven output enable signals
- Two global clock signals with optional inversion
- Enhanced interconnect resources for improved routability
- Fast input setup times provided by a dedicated path from I/O pin to macrocell registers
- Programmable output slew-rate control
- Programmable ground pins

- Software design support and automatic place-and-route provided by Altera's development systems for Windows-based PCs and Sun SPARCstation, and HP 9000 Series 700/800 workstations
- Additional design entry and simulation support provided by EDIF 2 0 0 and 3 0 0 netlist files, library of parameterized modules (LPM), Verilog HDL, VHDL, and other interfaces to popular EDA tools from manufacturers such as Cadence, Exemplar Logic, Mentor Graphics, OrCAD, Synopsys, Synplicity, and VeriBest
- Programming support with Altera's Master Programming Unit (MPU), MasterBlaster<sup>TM</sup> serial/universal serial bus (USB) communications cable, ByteBlasterMV<sup>TM</sup> parallel port download cable, and BitBlaster<sup>TM</sup> serial download cable, as well as programming hardware from third-party manufacturers and any Jam<sup>TM</sup> STAPL File (.jam), Jam Byte-Code File (.jbc), or Serial Vector Format File- (.svf) capable in-circuit tester

# General Description

MAX 7000A (including MAX 7000AE) devices are high-density, highperformance devices based on Altera's second-generation MAX architecture. Fabricated with advanced CMOS technology, the EEPROMbased MAX 7000A devices operate with a 3.3-V supply voltage and provide 600 to 10,000 usable gates, ISP, pin-to-pin delays as fast as 4.5 ns, and counter speeds of up to 227.3 MHz. MAX 7000A devices in the -4, -5, -6, -7, and some -10 speed grades are compatible with the timing requirements for 33 MHz operation of the PCI Special Interest Group (PCI SIG) *PCI Local Bus Specification, Revision 2.2*. See Table 2.

Table 2. MAX 7000A Speed Grades									
Device		Speed Grade							
	-4	-5	-6	-7	-10	-12			
EPM7032AE	<b>&gt;</b>			$\checkmark$	$\checkmark$				
EPM7064AE	<b>&gt;</b>			$\checkmark$	$\checkmark$				
EPM7128A			$\checkmark$	~	~	~			
EPM7128AE		~		$\checkmark$	$\checkmark$				
EPM7256A			$\checkmark$	$\checkmark$	$\checkmark$	$\checkmark$			
EPM7256AE		$\checkmark$		~	~				
EPM7512AE				$\checkmark$	$\checkmark$	$\checkmark$			

The MAX 7000A architecture supports 100% transistor-to-transistor logic (TTL) emulation and high-density integration of SSI, MSI, and LSI logic functions. It easily integrates multiple devices including PALs, GALs, and 22V10s devices. MAX 7000A devices are available in a wide range of packages, including PLCC, BGA, FineLine BGA, Ultra FineLine BGA, PQFP, and TQFP packages. See Table 3 and Table 4.

Table 3. MAX 700	OA Maximum U	lser I/O Pins	Note (1)			
Device	44-Pin PLCC	44-Pin TQFP	49-Pin Ultra FineLine BGA (2)	84-Pin PLCC	100-Pin TQFP	100-Pin FineLine BGA (3)
EPM7032AE	36	36				
EPM7064AE	36	36	41		68	68
EPM7128A				68	84	84
EPM7128AE				68	84	84
EPM7256A					84	
EPM7256AE					84	84
EPM7512AE						

Table 4. MAX 7000A Maximum User I/O PinsNote (1)								
Device	144-Pin TQFP	169-Pin Ultra FineLine BGA <i>(2)</i>	208-Pin PQFP	256-Pin BGA	256-Pin FineLine BGA (3)			
EPM7032AE								
EPM7064AE								
EPM7128A	100				100			
EPM7128AE	100	100			100			
EPM7256A	120		164		164			
EPM7256AE	120		164		164			
EPM7512AE	120		176	212	212			

#### Notes to tables:

- (1) When the IEEE Std. 1149.1 (JTAG) interface is used for in-system programming or boundary-scan testing, four I/O pins become JTAG pins.
- (2) All Ultra FineLine BGA packages are footprint-compatible via the SameFrame<sup>TM</sup> feature. Therefore, designers can design a board to support a variety of devices, providing a flexible migration path across densities and pin counts. Device migration is fully supported by Altera development tools. See "SameFrame Pin-Outs" on page 15 for more details.
- (3) All FineLine BGA packages are footprint-compatible via the SameFrame feature. Therefore, designers can design a board to support a variety of devices, providing a flexible migration path across densities and pin counts. Device migration is fully supported by Altera development tools. See "SameFrame Pin-Outs" on page 15 for more details.

MAX 7000A devices use CMOS EEPROM cells to implement logic functions. The user-configurable MAX 7000A architecture accommodates a variety of independent combinatorial and sequential logic functions. The devices can be reprogrammed for quick and efficient iterations during design development and debug cycles, and can be programmed and erased up to 100 times.

MAX 7000A devices contain from 32 to 512 macrocells that are combined into groups of 16 macrocells, called logic array blocks (LABs). Each macrocell has a programmable-AND/fixed-OR array and a configurable register with independently programmable clock, clock enable, clear, and preset functions. To build complex logic functions, each macrocell can be supplemented with both shareable expander product terms and highspeed parallel expander product terms, providing up to 32 product terms per macrocell.

MAX 7000A devices provide programmable speed/power optimization. Speed-critical portions of a design can run at high speed/full power, while the remaining portions run at reduced speed/low power. This speed/power optimization feature enables the designer to configure one or more macrocells to operate at 50% or lower power while adding only a nominal timing delay. MAX 7000A devices also provide an option that reduces the slew rate of the output buffers, minimizing noise transients when non-speed-critical signals are switching. The output drivers of all MAX 7000A devices can be set for 2.5 V or 3.3 V, and all input pins are 2.5-V, 3.3-V, and 5.0-V tolerant, allowing MAX 7000A devices to be used in mixed-voltage systems.

MAX 7000A devices are supported by Altera development systems, which are integrated packages that offer schematic, text—including VHDL, Verilog HDL, and the Altera Hardware Description Language (AHDL)—and waveform design entry, compilation and logic synthesis, simulation and timing analysis, and device programming. The software provides EDIF 2 0 0 and 3 0 0, LPM, VHDL, Verilog HDL, and other interfaces for additional design entry and simulation support from other industry-standard PC- and UNIX-workstation-based EDA tools. The software runs on Windows-based PCs, as well as Sun SPARCstation, and HP 9000 Series 700/800 workstations.

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For more information on development tools, see the *MAX+PLUS II Programmable Logic Development System & Software Data Sheet* and the *Quartus Programmable Logic Development System & Software Data Sheet*.

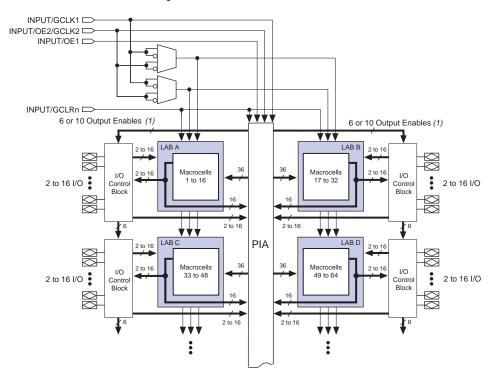


Figure 1. MAX 7000A Device Block Diagram

#### Note:

(1) EPM7032AE, EPM7064AE, EPM7128A, EPM7128AE, EPM7256A, and EPM7256AE devices have six output enables. EPM7512AE devices have 10 output enables.

#### Logic Array Blocks

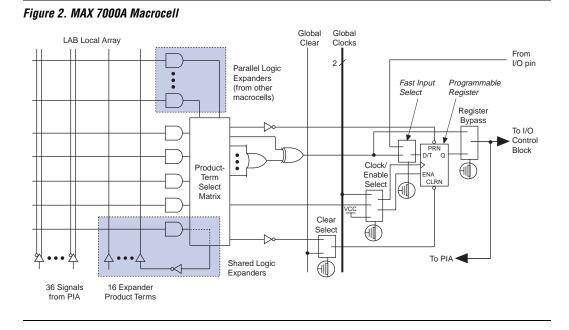
The MAX 7000A device architecture is based on the linking of high-performance LABs. LABs consist of 16-macrocell arrays, as shown in Figure 1. Multiple LABs are linked together via the PIA, a global bus that is fed by all dedicated input pins, I/O pins, and macrocells.

Each LAB is fed by the following signals:

- **3**6 signals from the PIA that are used for general logic inputs
- Global controls that are used for secondary register functions
- Direct input paths from I/O pins to the registers that are used for fast setup times

#### Macrocells

MAX 7000A macrocells can be individually configured for either sequential or combinatorial logic operation. The macrocells consist of three functional blocks: the logic array, the product-term select matrix, and the programmable register. Figure 2 shows a MAX 7000A macrocell.



Combinatorial logic is implemented in the logic array, which provides five product terms per macrocell. The product-term select matrix allocates these product terms for use as either primary logic inputs (to the OR and XOR gates) to implement combinatorial functions, or as secondary inputs to the macrocell's register preset, clock, and clock enable control functions.

Two kinds of expander product terms ("expanders") are available to supplement macrocell logic resources:

- Shareable expanders, which are inverted product terms that are fed back into the logic array
- Parallel expanders, which are product terms borrowed from adjacent macrocells

The Altera development system automatically optimizes product-term allocation according to the logic requirements of the design.

For registered functions, each macrocell flipflop can be individually programmed to implement D, T, JK, or SR operation with programmable clock control. The flipflop can be bypassed for combinatorial operation. During design entry, the designer specifies the desired flipflop type; the Altera software then selects the most efficient flipflop operation for each registered function to optimize resource utilization.

Each programmable register can be clocked in three different modes:

- Global clock signal. This mode achieves the fastest clock-to-output performance.
- Global clock signal enabled by an active-high clock enable. A clock enable is generated by a product term. This mode provides an enable on each flipflop while still achieving the fast clock-to-output performance of the global clock.
- Array clock implemented with a product term. In this mode, the flipflop can be clocked by signals from buried macrocells or I/O pins.

Two global clock signals are available in MAX 7000A devices. As shown in Figure 1, these global clock signals can be the true or the complement of either of the global clock pins, GCLK1 or GCLK2.

Each register also supports asynchronous preset and clear functions. As shown in Figure 2, the product-term select matrix allocates product terms to control these operations. Although the product-term-driven preset and clear from the register are active high, active-low control can be obtained by inverting the signal within the logic array. In addition, each register clear function can be individually driven by the active-low dedicated global clear pin (GCLRn). Upon power-up, each register in a MAX 7000AE device may be set to either a high or low state. This power-up state is specified at design entry. Upon power-up, each register in EPM7128A and EPM7256A devices are set to a low state.

All MAX 7000A I/O pins have a fast input path to a macrocell register. This dedicated path allows a signal to bypass the PIA and combinatorial logic and be clocked to an input D flipflop with an extremely fast (as low as 2.5 ns) input setup time.

#### **Expander Product Terms**

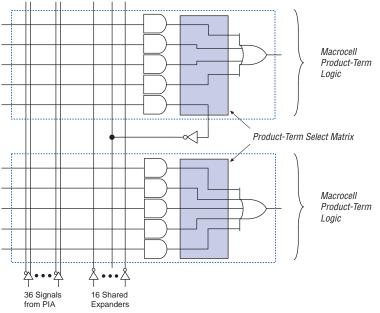
Although most logic functions can be implemented with the five product terms available in each macrocell, more complex logic functions require additional product terms. Another macrocell can be used to supply the required logic resources. However, the MAX 7000A architecture also offers both shareable and parallel expander product terms that provide additional product terms directly to any macrocell in the same LAB. These expanders help ensure that logic is synthesized with the fewest possible logic resources to obtain the fastest possible speed.

#### Shareable Expanders

Each LAB has 16 shareable expanders that can be viewed as a pool of uncommitted single product terms (one from each macrocell) with inverted outputs that feed back into the logic array. Each shareable expander can be used and shared by any or all macrocells in the LAB to build complex logic functions. A small delay ( $t_{SEXP}$ ) is incurred when shareable expanders are used. Figure 3 shows how shareable expanders can feed multiple macrocells.



Shareable expanders can be shared by any or all macrocells in an LAB.



#### Parallel Expanders

Parallel expanders are unused product terms that can be allocated to a neighboring macrocell to implement fast, complex logic functions. Parallel expanders allow up to 20 product terms to directly feed the macrocell OR logic, with five product terms provided by the macrocell and 15 parallel expanders provided by neighboring macrocells in the LAB.

The compiler can allocate up to three sets of up to five parallel expanders to the macrocells that require additional product terms. Each set of five parallel expanders incurs a small, incremental timing delay ( $t_{PEXP}$ ). For example, if a macrocell requires 14 product terms, the compiler uses the five dedicated product terms within the macrocell and allocates two sets of parallel expanders; the first set includes five product terms, and the second set includes four product terms, increasing the total delay by  $2 \times t_{PEXP}$ .

Two groups of eight macrocells within each LAB (e.g., macrocells 1 through 8 and 9 through 16) form two chains to lend or borrow parallel expanders. A macrocell borrows parallel expanders from lower-numbered macrocells. For example, macrocell 8 can borrow parallel expanders from macrocell 7, from macrocells 7 and 6, or from macrocells 7, 6, and 5. Within each group of eight, the lowest-numbered macrocell can only lend parallel expanders, and the highest-numbered macrocell can only borrow them. Figure 4 shows how parallel expanders can be borrowed from a neighboring macrocell.



For more information on using the Jam STAPL language, see *Application Note 88 (Using the Jam Language for ISP & ICR via an Embedded Processor)* and *Application Note 122 (Using Jam STAPL for ISP & ICR via an Embedded Processor)*.

ISP circuitry in MAX 7000AE devices is compliant with the IEEE Std. 1532 specification. The IEEE Std. 1532 is a standard developed to allow concurrent ISP between multiple PLD vendors.

## **Programming Sequence**

During in-system programming, instructions, addresses, and data are shifted into the MAX 7000A device through the TDI input pin. Data is shifted out through the TDO output pin and compared against the expected data.

Programming a pattern into the device requires the following six ISP stages. A stand-alone verification of a programmed pattern involves only stages 1, 2, 5, and 6.

- 1. *Enter ISP*. The enter ISP stage ensures that the I/O pins transition smoothly from user mode to ISP mode. The enter ISP stage requires 1 ms.
- 2. *Check ID*. Before any program or verify process, the silicon ID is checked. The time required to read this silicon ID is relatively small compared to the overall programming time.
- 3. *Bulk Erase*. Erasing the device in-system involves shifting in the instructions to erase the device and applying one erase pulse of 100 ms.
- 4. *Program*. Programming the device in-system involves shifting in the address and data and then applying the programming pulse to program the EEPROM cells. This process is repeated for each EEPROM address.
- 5. *Verify.* Verifying an Altera device in-system involves shifting in addresses, applying the read pulse to verify the EEPROM cells, and shifting out the data for comparison. This process is repeated for each EEPROM address.
- 6. *Exit ISP*. An exit ISP stage ensures that the I/O pins transition smoothly from ISP mode to user mode. The exit ISP stage requires 1 ms.

The instruction register length of MAX 7000A devices is 10 bits. The user electronic signature (UES) register length in MAX 7000A devices is 16 bits. The MAX 7000AE USERCODE register length is 32 bits. Tables 9 and 10 show the boundary-scan register length and device IDCODE information for MAX 7000A devices.

Table 9. MAX 7000A Boundary-Scan Register Length						
Device	Boundary-Scan Register Length					
EPM7032AE	96					
EPM7064AE	192					
EPM7128A	288					
EPM7128AE	288					
EPM7256A	480					
EPM7256AE	480					
EPM7512AE	624					

Table 10. 32 <sup>.</sup>	Table 10. 32-Bit MAX 7000A Device IDCODE Note (1)								
Device		IDCODE (32 Bits)							
	Version (4 Bits)	(4 Bits) Identity (11 Bits)							
EPM7032AE	0001	0111 0000 0011 0010	00001101110	1					
EPM7064AE	0001	0111 0000 0110 0100	00001101110	1					
EPM7128A	0000	0111 0001 0010 1000	00001101110	1					
EPM7128AE	0001	0111 0001 0010 1000	00001101110	1					
EPM7256A	0000	0111 0010 0101 0110	00001101110	1					
EPM7256AE	0001	0111 0010 0101 0110	00001101110	1					
EPM7512AE	0001	0111 0101 0001 0010	00001101110	1					

#### Notes:

(1) The most significant bit (MSB) is on the left.

(2) The least significant bit (LSB) for all JTAG IDCODEs is 1.



See *Application Note 39 (IEEE 1149.1 (JTAG) Boundary-Scan Testing in Altera Devices)* for more information on JTAG BST.

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#### Figure 9. MAX 7000A AC Test Conditions

Power supply transients can affect AC measurements. Simultaneous transitions of multiple outputs should be avoided for accurate measurement. Threshold tests 703 Ω [521 Ω] *≶* must not be performed under AC conditions. Large-amplitude, fast-ground-Device Output current transients normally occur as the device outputs discharge the load capacitances. When these transients flow through the parasitic inductance between 586 Ω [481 Ω] *≥* the device ground pin and the test system ground, significant reductions in Device input observable noise immunity can result. rise and fall Numbers in brackets are for 2.5-V times < 2 ns outputs. Numbers without brackets are for 3.3-V outputs.

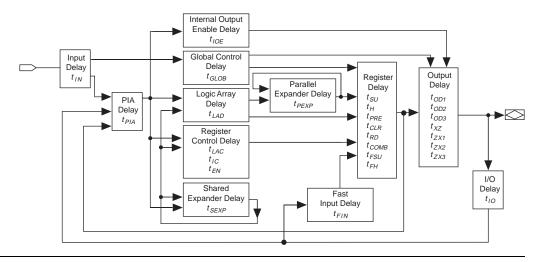
# Operating Conditions

Tables 13 through 16 provide information on absolute maximum ratings, recommended operating conditions, operating conditions, and capacitance for MAX 7000A devices.

Table 1	Table 13. MAX 7000A Device Absolute Maximum Ratings     Note (1)									
Symbol	Parameter	Conditions	Min	Max	Unit					
V <sub>CC</sub>	Supply voltage	With respect to ground (2)	-0.5	4.6	V					
VI	DC input voltage		-2.0	5.75	V					
I <sub>OUT</sub>	DC output current, per pin		-25	25	mA					
T <sub>STG</sub>	Storage temperature	No bias	-65	150	°C					
T <sub>A</sub>	Ambient temperature	Under bias	-65	135	°C					
Τ <sub>J</sub>	Junction temperature	BGA, FineLine BGA, PQFP, and TQFP packages, under bias		135	°C					

Table 1	4. MAX 7000A Device Recomm	ended Operating Conditions			
Symbol	Parameter	Conditions	Min	Max	Unit
V <sub>CCINT</sub>	Supply voltage for internal logic and input buffers	(3), (13)	3.0	3.6	V
V <sub>CCIO</sub>	Supply voltage for output drivers, 3.3-V operation	(3)	3.0	3.6	V
	Supply voltage for output drivers, 2.5-V operation	(3)	2.3	2.7	V
V <sub>CCISP</sub>	Supply voltage during in- system programming		3.0	3.6	V
VI	Input voltage	(4)	-0.5	5.75	V
Vo	Output voltage		0	V <sub>CCIO</sub>	V
T <sub>A</sub>	Ambient temperature	Commercial range	0	70	°C
		Industrial range (5)	-40	85	°C
TJ	Junction temperature	Commercial range	0	90	°C
		Industrial range (5)	-40	105	°C
		Extended range (5)	-40	130	°C
t <sub>R</sub>	Input rise time			40	ns
t <sub>F</sub>	Input fall time			40	ns

Figure 11. MAX 7000A Timing Model



The timing characteristics of any signal path can be derived from the timing model and parameters of a particular device. External timing parameters, which represent pin-to-pin timing delays, can be calculated as the sum of internal parameters. Figure 12 shows the timing relationship between internal and external delay parameters.



See *Application Note 94 (Understanding MAX 7000 Timing)* for more information.

Tables 17 through 30 show EPM7032AE, EPM7064AE, EPM7128AE, EPM7256AE, EPM7512AE, EPM7128A, and EPM7256A timing information.

Table 1	7. EPM7032AE External Timi	ng Parameters	Note (	(1)					
Symbol	Parameter	Conditions	Speed Grade						Unit
			-	4	-	7	-1	10	
			Min	Max	Min	Max	Min	Max	
t <sub>PD1</sub>	Input to non-registered output	C1 = 35 pF (2)		4.5		7.5		10	ns
t <sub>PD2</sub>	I/O input to non-registered output	C1 = 35 pF (2)		4.5		7.5		10	ns
t <sub>SU</sub>	Global clock setup time	(2)	2.9		4.7		6.3		ns
t <sub>H</sub>	Global clock hold time	(2)	0.0		0.0		0.0		ns
t <sub>FSU</sub>	Global clock setup time of fast input		2.5		3.0		3.0		ns
t <sub>FH</sub>	Global clock hold time of fast input		0.0		0.0		0.0		ns
t <sub>CO1</sub>	Global clock to output delay	C1 = 35 pF	1.0	3.0	1.0	5.0	1.0	6.7	ns
t <sub>CH</sub>	Global clock high time		2.0		3.0		4.0		ns
t <sub>CL</sub>	Global clock low time		2.0		3.0		4.0		ns
t <sub>ASU</sub>	Array clock setup time	(2)	1.6		2.5		3.6		ns
t <sub>AH</sub>	Array clock hold time	(2)	0.3		0.5		0.5		ns
t <sub>ACO1</sub>	Array clock to output delay	C1 = 35 pF (2)	1.0	4.3	1.0	7.2	1.0	9.4	ns
t <sub>ACH</sub>	Array clock high time		2.0		3.0		4.0		ns
t <sub>ACL</sub>	Array clock low time		2.0		3.0		4.0		ns
t <sub>CPPW</sub>	Minimum pulse width for clear and preset	(3)	2.0		3.0		4.0		ns
t <sub>CNT</sub>	Minimum global clock period	(2)		4.4		7.2		9.7	ns
f <sub>CNT</sub>	Maximum internal global clock frequency	(2), (4)	227.3		138.9		103.1		MHz
t <sub>ACNT</sub>	Minimum array clock period	(2)		4.4		7.2		9.7	ns
f <sub>ACNT</sub>	Maximum internal array clock frequency	(2), (4)	227.3		138.9		103.1		MHz

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Symbol	Parameter	Conditions	Speed Grade							
			-	4	-	7	-10			
			Min	Max	Min	Max	Min	Max		
t <sub>IC</sub>	Array clock delay			1.2		2.0		2.5	ns	
t <sub>EN</sub>	Register enable time			0.6		1.0		1.2	ns	
t <sub>GLOB</sub>	Global control delay			0.8		1.3		1.9	ns	
t <sub>PRE</sub>	Register preset time			1.2		1.9		2.6	ns	
t <sub>CLR</sub>	Register clear time			1.2		1.9		2.6	ns	
t <sub>PIA</sub>	PIA delay	(2)		0.9		1.5		2.1	ns	
t <sub>LPA</sub>	Low-power adder	(6)		2.5		4.0		5.0	ns	

Symbol	Parameter	Conditions		Speed Grade				Unit	
			-;	5	-7		-1	0	
			Min	Max	Min	Max	Min	Max	
t <sub>PD1</sub>	Input to non- registered output	C1 = 35 pF (2)		5.5		7.5		10	ns
t <sub>PD2</sub>	I/O input to non- registered output	C1 = 35 pF (2)		5.5		7.5		10	ns
t <sub>SU</sub>	Global clock setup time	(2)	3.9		5.2		6.9		ns
t <sub>H</sub>	Global clock hold time	(2)	0.0		0.0		0.0		ns
t <sub>FSU</sub>	Global clock setup time of fast input		2.5		3.0		3.0		ns
t <sub>FH</sub>	Global clock hold time of fast input		0.0		0.0		0.0		ns
t <sub>CO1</sub>	Global clock to output delay	C1 = 35 pF	1.0	3.5	1.0	4.8	1.0	6.4	ns
t <sub>CH</sub>	Global clock high time		2.0		3.0		4.0		ns
t <sub>CL</sub>	Global clock low time		2.0		3.0		4.0		ns
t <sub>ASU</sub>	Array clock setup time	(2)	2.0		2.7		3.6		ns
t <sub>AH</sub>	Array clock hold time	(2)	0.2		0.3		0.5		ns
t <sub>ACO1</sub>	Array clock to output delay	C1 = 35 pF (2)	1.0	5.4	1.0	7.3	1.0	9.7	ns
t <sub>ACH</sub>	Array clock high time		2.0		3.0		4.0		ns
t <sub>ACL</sub>	Array clock low time		2.0		3.0		4.0		ns
t <sub>CPPW</sub>	Minimum pulse width for clear and preset	(3)	2.0		3.0		4.0		ns
t <sub>CNT</sub>	Minimum global clock period	(2)		5.8		7.9		10.5	ns
f <sub>CNT</sub>	Maximum internal global clock frequency	(2), (4)	172.4		126.6		95.2		MHz
t <sub>acnt</sub>	Minimum array clock period	(2)		5.8		7.9		10.5	ns
f <sub>acnt</sub>	Maximum internal array clock frequency	(2), (4)	172.4		126.6		95.2		MHz

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Symbol	Parameter	Conditions	Speed Grade								Unit
			-	6	-7		-10		-12		
			Min	Max	Min	Max	Min	Max	Min	Max	
t <sub>IN</sub>	Input pad and buffer delay			0.6		0.7		0.9		1.1	ns
t <sub>IO</sub>	I/O input pad and buffer delay			0.6		0.7		0.9		1.1	ns
t <sub>FIN</sub>	Fast input delay			2.7		3.1		3.6		3.9	ns
t <sub>SEXP</sub>	Shared expander delay			2.5		3.2		4.3		5.1	ns
t <sub>PEXP</sub>	Parallel expander delay			0.7		0.8		1.1		1.3	ns
t <sub>LAD</sub>	Logic array delay			2.4		3.0		4.1		4.9	ns
t <sub>LAC</sub>	Logic control array delay			2.4		3.0		4.1		4.9	ns
t <sub>IOE</sub>	Internal output enable delay			0.0		0.0		0.0		0.0	ns
t <sub>OD1</sub>	Output buffer and pad delay, slow slew rate = off $V_{CCIO} = 3.3 V$	C1 = 35 pF		0.4		0.6		0.7		0.9	ns
t <sub>OD2</sub>	Output buffer and pad delay, slow slew rate = off $V_{CCIO} = 2.5 V$	C1 = 35 pF (5)		0.9		1.1		1.2		1.4	ns
t <sub>OD3</sub>	Output buffer and pad delay, slow slew rate = on $V_{CCIO} = 2.5$ V or 3.3 V	C1 = 35 pF		5.4		5.6		5.7		5.9	ns
t <sub>ZX1</sub>	Output buffer enable delay, slow slew rate = off $V_{CCIO} = 3.3 V$	C1 = 35 pF		4.0		4.0		5.0		5.0	ns
t <sub>ZX2</sub>	Output buffer enable delay, slow slew rate = off $V_{CCIO} = 2.5 V$	C1 = 35 pF (5)		4.5		4.5		5.5		5.5	ns
t <sub>ZX3</sub>	Output buffer enable delay, slow slew rate = on $V_{CCIO} = 3.3 V$	C1 = 35 pF		9.0		9.0		10.0		10.0	ns
t <sub>XZ</sub>	Output buffer disable delay	C1 = 5 pF		4.0		4.0		5.0		5.0	ns
t <sub>SU</sub>	Register setup time		1.9		2.4		3.1		3.8		ns
t <sub>H</sub>	Register hold time		1.5		2.2		3.3		4.3		ns
t <sub>FSU</sub>	Register setup time of fast input		0.8		1.1		1.1		1.1		ns
t <sub>FH</sub>	Register hold time of fast input		1.7		1.9		1.9		1.9		ns

## Figure 21. 208-Pin PQFP Package Pin-Out Diagram

Package outline not drawn to scale.

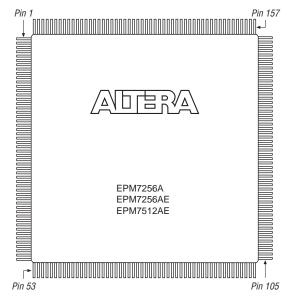
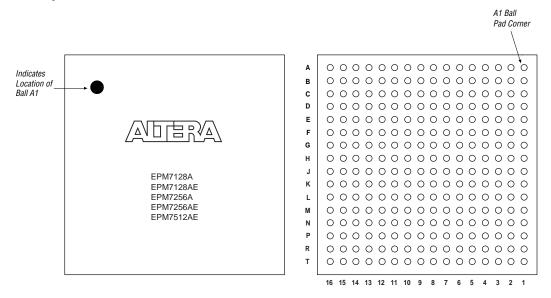


Figure 23. 256-Pin FineLine BGA Package Pin-Out Diagram

Package outline not drawn to scale.



# Revision History

The information contained in the *MAX 7000A Programmable Logic Device Data Sheet* version 4.5 supersedes information published in previous versions.

## Version 4.5

The following changes were made in the *MAX 7000A Programmable Logic Device Data Sheet* version 4.5:

■ Updated text in the "Power Sequencing & Hot-Socketing" section.

## Version 4.4

The following changes were made in the *MAX 7000A Programmable Logic Device Data Sheet* version 4.4:

- Added Tables 5 through 7.
  - Added "Programming Sequence" on page 17 and "Programming Times" on page 18.